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 Fujiwara, H.; Zhong Zhang; Hatta, H.; Koshimizu, H.;
Industrial Electronics Society, 2004. IECON 2004. 30th Annual Conference of I
 Volume 2, 2-6 Nov. 2004 Page(s):1252 - 1257 Vol. 2
 Digital Object Identifier 10.1109/IECON.2004.1431755
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 Fujiwara, H.; Zhong Zhang; Toda, H.; Kawabata, H.;
Computational Intelligence in Robotics and Automation, 2003. Proceedings. 20
International Symposium on
 Volume 3, 16-20 July 2003 Page(s):1427 - 1432 vol.3
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using wavelet shrinkage
 Fujiwara, H.; Zhong Zhang; Hashimoto, K.;
Robotics and Automation, 2001. Proceedings 2001 ICRA. IEEE International C
 Volume 4, 2001 Page(s):3529 - 3534 vol.4
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 Abuazza, A.; Brabazon, D.; El-Baradie, M.A.;
Lasers and Electro-Optics Society, 2002. LEOS 2002. The 15th Annual Meetin
 Volume 1, 10-14 Nov. 2002 Page(s):175 - 176 vol.1
 Digital Object Identifier 10.1109/LEOS.2002.1133984
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 Shi Ding-Ji; Wang Shou-Yan; Huang Han-Wen; Wu Bo-Xin;
Industrial Technology, 1994. Proceedings of the IEEE International Conference
 5-9 Dec. 1994 Page(s):659 - 664
 Digital Object Identifier 10.1109/ICIT.1994.467060

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Fernandez, C.; Fernandez, S.; Campoy, P.; Aracil, R.;
[Industrial Electronics, Control and Instrumentation, 1994. IECON '94., 20th Inte](#)
[Conference on](#)
Volume 2, 5-9 Sept. 1994 Page(s):867 - 872 vol.2
Digital Object Identifier 10.1109/IECON.1994.397901
[AbstractPlus](#) | Full Text: [PDF\(520 KB\)](#) IEEE CNF
[Rights and Permissions](#)
- ☒ 7. **Inspection of surface defects using optimal FIR filters**
Kumar, A.;
[Acoustics, Speech, and Signal Processing, 2003. Proceedings. \(ICASSP '03\).](#)
[International Conference on](#)
Volume 2, 6-10 April 2003 Page(s):II - 241-4 vol.2
Digital Object Identifier 10.1109/ICASSP.2003.1202339
[AbstractPlus](#) | Full Text: [PDF\(370 KB\)](#) IEEE CNF
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- ☒ 8. **Defect detection in textured materials using Gabor filters**
Kumar, A.; Pang, G.;
[Industry Applications Conference, 2000. Conference Record of the 2000 IEEE](#)
Volume 2, 8-12 Oct. 2000 Page(s):1041 - 1047 vol.2
Digital Object Identifier 10.1109/IAS.2000.881960
[AbstractPlus](#) | Full Text: [PDF\(1072 KB\)](#) IEEE CNF
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Chi-Ho Chan; Pang, G.;
[Industry Applications Conference, 1999. Thirty-Fourth IAS Annual Meeting. Co](#)
[of the 1999 IEEE](#)
Volume 3, 3-7 Oct. 1999 Page(s):1743 - 1750 vol.3
Digital Object Identifier 10.1109/IAS.1999.805975
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Byeong-Mook Chung; Che-Seung Cho; Moo-Jin Park;
[Control, Automation, Robotics and Vision Conference, 2004. ICARCV 2004 8th](#)
Volume 3, 6-9 Dec. 2004 Page(s):1826 - 1831 Vol. 3
Digital Object Identifier 10.1109/ICARCV.2004.1469436
[AbstractPlus](#) | Full Text: [PDF](#)(353 KB) IEEE CNF
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- ☒ 2. **Wavelet analysis to fabric defects detection in weaving processes**
Sungshin Kim; Man Hung Lee; Kwang-Bang Woo;
[Industrial Electronics, 1999. ISIE '99. Proceedings of the IEEE International Sy](#)
Volume 3, 12-16 July 1999 Page(s):1406 - 1409 vol.3
Digital Object Identifier 10.1109/ISIE.1999.796918
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE CNF
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- ☒ 3. **Color inspection of printed texture using scanner and NN model**
Byeong-Mook Chung; Che-Seung Cho; Moo-Jin Park;
[Industrial Technology, 2004. IEEE ICIT '04. 2004 IEEE International Conferenc](#)
Volume 2, 8-10 Dec. 2004 Page(s):1100 - 1105 Vol. 2
Digital Object Identifier 10.1109/ICIT.2004.1490231
[AbstractPlus](#) | Full Text: [PDF](#)(400 KB) IEEE CNF
[Rights and Permissions](#)
- ☒ 4. **On-line defect detection for weaving systems**
Dorrity, J.L.; Vachtsevanos, G.;
[Textile, Fiber and Film Industry Technical Conference, 1996., IEEE 1996 Annu](#)
15-16 May 1996 Page(s):6 pp.
Digital Object Identifier 10.1109/TEXCON.1996.506352
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